## Applicant(s)/Patent Under Application/Control No. Reexamination 09/230,001 DE HEUS, EVERT BASTIAAN Natice of References Cited Examiner Art Unit Page 1 of 1 Krisanne M. Thornton 1744 **U.S. PATENT DOCUMENTS** Date Document Number Classification Name ary Code-Number-Kind Code MM-YYYY 422 US -263258 04-1981 Kalasek 113 Α 422 26 UΈ £38447 12-1980 Wolff В 422 26 С U5- 340248 11-1998 Ongaro D Usi US Ε US F US G US Н US 1 Uo J US Κ Us L US Μ FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name any Code-Number-Kind Code MM-YYYY Ν 0 Ρ

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